Welcome to ICST 2017 Day-1
General Chairs: Yasuharu Nishi and Atif Memon
The conference offers

I nteresting presentations
C hallenging thoughts
S trong results
T ailored demonstrations
378 Attendees

<table>
<thead>
<tr>
<th>Category</th>
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<tr>
<td>Univ.</td>
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<td>Industry</td>
<td>163</td>
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<td>Institutes</td>
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<td>Others</td>
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Hashtag: #ICST2017
Sponsors
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<td><strong>Platinum sponsors</strong></td>
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<td><strong>Special sponsorship</strong></td>
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Multi-Track Event - Best of Research & Practice

- **Research Issues in Software Testing**
  - Technical Research Track
  - Doctoral Symposium
  - Posters Track

- **Applying Software Testing**
  - Industry Track
  - Testing Tools Papers Track
  - Testing Tools Demonstrations Track
  - Software Testing Contest
## Workshops (yesterday)

**March 13, 2017**

<table>
<thead>
<tr>
<th>Workshop</th>
<th>Description</th>
<th>URL</th>
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<tbody>
<tr>
<td>Mutation: Mutation Analysis</td>
<td><strong>Mutation: Mutation Analysis</strong></td>
<td><a href="https://sites.google.com/site/mutation2017/">https://sites.google.com/site/mutation2017/</a></td>
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</table>
# Workshops (Friday)

**March 17, 2017**

<table>
<thead>
<tr>
<th>Workshop</th>
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<tr>
<td>A-MOST: Advances in Model Based Testing</td>
<td><a href="http://a-most17.zen-tools.com/">http://a-most17.zen-tools.com/</a></td>
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# Doctoral Symposium
Main Conference Program Events

- **Keynotes**
  - John Micco (Google) on *The State of Continuous Integration Testing at Google*
  - Kenji Nishikawa (Toyota) on *Testing & Validation Requirements for Automated Driving Technology*
  - Andreas Zeller (Saarland University) on *Model-Based Testing and Model Inference: Better Together!*

- **Special Sessions**
  - Tatsuo Tomita (IT Promotion Agency - IPA) on *Aiming to realize a "Reliable IT Society"*
  - Takaaki Matsumoto (IPA) on *Systematic Approach toward Dependable System Development*
  - Koichi Tanizaki (Veriserve) on *R&D activities on test processes, analysis and design in Veriserve*
  - Justin R. Morris (NASA) on *Usage of software testing at NASA IV&V (with VIDEO)*
  - Maria Hernek (ESA) on *Independent Software V&V of Flight Software Development*
  - Naoko Okubo (JAXA) on *How JAXA uses software testing for IV&V, and what is the needs*
  - Hideki Nomoto (Japan Manned Space Systems) on *Integrated Formal Analysis for Software IV&V*
Main Conference Program Events

● Panels
  ○ Bleeding-Edge Testing Challenges that the Software Industry Faces
    - an Invitation to Researchers to Address these Challenges
    ■ Session chair: Atif Memon (University of Maryland)
    ■ Panelists:
      ● John Micco (Google), Bao Nguyen (Google), Murat Ozturk (Google), Adithya Nagarajan (Apple)
  ○ Quality and testing in Software Engineering curriculum
    ■ Session chair: Shlomo Mark (SCE)
    ■ Panelists:
      ● Ina Schieferdeker (Fraunhofer FOKUS), Tanja Vos (Open University in The Netherlands), Shuji Morisaki (Nagoya University), Jens Krinke (University College London)
● Open Steering Committee Meeting
Conference Layout

- Registration (2nd Floor; Foyer)
- Breakfast (Ground Floor; 8:15)
- Sessions (Room 201-204)
- Breaks (Ground floor; 10:30 & 15:30)
- Lunch (in Conference rooms, Lobby and Cafeteria; 12:30-14:00)
- Demos (Room 204, Tue; 11:00)
- Contests (Room 204, Wed; 11:00)
- Posters (Ground floor - red boxes; Tuesday afternoon - Thursday morning)
Social Events

Welcome Reception Tonight

- Time: 19:00-21:00
- Cafeteria on the 1st Floor of Building 63
Social Events

*Banquet Tomorrow Night*

- Two venues in the same skyscraper “Sunshine 60” in Ikebukuro
  - You can enjoy a wonderful night view
- Main venue: Restaurant: “Sunshine Cruise Cruise”
  - This is not a cruise; it’s a restaurant!!
  - Conversation in English
- Satellite venue: Restaurant “Ocean Casita”
  - Conversation in Japanese
  - No needs for pre-subscription
- Banquet Starts at Time: 7:30PM
- Transportation: Buses
  - From the university and back to stations and hotels
  - To get directions via Google Maps: [https://goo.gl/maps/xT9c9FUUqxo](https://goo.gl/maps/xT9c9FUUqxo)
Volunteers & Staff

If you want it for souvenir, we'll sell it for JPY5,000. JPY7,500 with Atif's autograph!

Hashtag: #ICST2017
Organizing Team
Notices from Local arrangement chairs
Chio Fujimoto and Satomi Yoshizawa

- WiFi - Refresh every 2 hours!
- Check everything is in your bag
  - “Certification” is in your badge
Notices from Local arrangement chairs
Chio Fujimoto and Satomi Yoshizawa

- Never take a receiver out to your home!
  - 同時通訳用レシーバーは必ず返却してください
- Questions should be asked in English
  - 質疑応答時の質問は英語でお願いします。日 → 英の同時通訳はありません。
- In case of emergency situations, please follow the local team members.
- Don’t hesitate to come to the registration desk if you have any question or problem
Greetings from guests

Mr. Kenji Onishi
Vice president
ASTER, Association of Software Test Engineering Japan
(The co-organizer with IEEE of ICST 2017 Tokyo)
WELCOME TO ICST  2017/14th /March
ABOUT ASTER

ASTER : Association of Software Test Engineering

is a non-profit organization which undertakes research, promotion, education and international collaboration for software testing and software quality. ASTER was established at Tokyo in 2006. Our Directors and members are working as volunteers.

This NPO is constituted by industry-university experts.

URL: http://aster.or.jp/
ABOUT ASTER

Symposium

JSTQB

R&D

International Activities

Education

Japan Symposium on Software Testing

Software Test Design Contest

Zengo Award

ICST 2017

InSTA 2017

Study Groups

ASTA

ISO/IEC JTC1/SC7/WG26
Greetings from guests

Mr. Yoichi Fujii
President
IVIA, IT Verification Industry Association
Welcome to Waseda University!
Welcome to the Research Track!

PC Chairs:

Ina Schieferdecker
Fraunhofer FOKUS / Technische Universität Berlin, Germany

Hironori Washizaki
Waseda University, Global Software Engineering Laboratory
/ National Institute of Informatics / SYSTEM INFORMATION, Japan
ICST 2017
13-17 March 2017, Tokyo, Japan

http://www.sekaichizu.jp/
Geographic Distribution about N. Papers 2017
ICST 2017
13-17 March 2017,
Tokyo, Japan

135 submissions
36 accepted full papers (27%)
8 accepted short papers
<table>
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<th>Sessions</th>
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Adopted from the slide made by Keizo Tatsumi
Papers Nominated for Best Paper Award


• *Incremental Deductive Verification for Relational Model Transformations*, Zheng Cheng and Massimo Tisi.


• *The Fitness Function for the Job: Search-Based Generation of Test Suites that Detect Real Faults*, Gregory Gay.

• *JavaScript: The (Un)covered Parts*, Amin Milani Fard and Ali Mesbah.
Best Paper Award
- *Symbolic Complexity Analysis using Context-preserving Histories*
  Kasper Luckow, Rody Kersten and Corina Pasareanu.
  Room 201, 14:00-15:30 Mar 14

Best Reviewer Awards (for PC members)
- will be announced at the dinner on Mar 15

Best Presentation Award (for full papers)
- Remember to vote!
- will be announced at the closing session on Mar 16

Industry Track

Program Chairs:
- Bao Nguyen, Google, USA
- Xun Yuan, Google, USA

Program Committee:
- Cyrille Artho, KTH Royal Inst. of Tech.
- Ishan Banerjee, VMware, USA
- Teng Long, Google, USA
- Adithya Nagarajan, Apple, USA
- Hung Nguyen, Google, USA
- John Penix, Google, USA
- Qing Xie, Auction.com, USA

- Total submissions: 18
- Accepted papers: 5
- Acceptance rate: 28%

Best Industry Track Paper:
Towards A Testbed for Automotive Cybersecurity by Daniel Fowler, Madeline Chesh, Jeremy Bryans and Siraj Shaikh
Testing Tools PAPERS Track

Program Chairs
- Domenico Amalfitano, Italy
- Tatsuhiro Tsuchiya, Japan

Program Committee
- Mariano Ceccato, Italy
- Eun-Hye Choi, Japan
- Damiano Distante, Italy
- Takashi Ishio, Japan
- Yang Liu, Singapore
- Ana Paiva, Portugal
- Karthik Pattabiraman, Canada
- Alexander Pretschner, Germany
- José Miguel Rojas, UK
- Stefano Scala, Italy
- Hideo Tanida, Japan
- Porfirio Tramontana, Italy
- Xiao Qu, USA
- Zijiang Yang, USA

- Total submissions: 29
- Accepted papers: 10
- Acceptance rate: 34%

Best Tools Track Paper
*Accelerating Test Automation through a Domain Specific Language*
Anurag Dwarakanath, Dipin Era, Aditya Priyadarshi, Neville Dubash and Sanjay Podder.
Tool DEMOS Track

PC Chairs
- Ana C. R. Paiva
- Zhenyu Chen

- Submitted: 8
- Accepted: 7

Remember to vote for Best Demo Award!
POSTERS Track

PC Chair
● Pekka Aho, VTT, Finland

PC Members
● Ceren Şahin Gebizli, Vestel Electronics, Turkey
● Teemu Kanstrén, VTT, Finland
● Olli-Pekka Puolitaival, Polar Electro, Finland

● 16 submissions
● 13 accepted

Remember to vote for Best Poster!!
Today’s Keynote

The State of Continuous Integration Testing at Google

John Micco, Google, USA